

# *Method and apparatus for scanning a specimen using an optical imaging system*

## Abstract

The invention is based on an apparatus and a method for scanning specimens (1) using an optical imaging system (3) and a scanning stage (2), images of the specimen (1) being acquired by means of a camera (4), and/or measurements on the specimen (1) being made by means of an optical measurement device (5), at specimen points  $X_p, Y_p$ . For that purpose, the scanning stage (2) is calibrated by obtaining and storing height values  $Z$  at different calibration positions  $X, Y$  of the scanning stage (2), and thereby generating a running height profile of the scanning stage (2). For the scanning of specimens (1), the specimen height positions  $Z_p$  at specimen points  $X_p, Y_p$  are determined by means of a reference height  $Z_{ref}$  of the specimen (1) together with the running height profile of the scanning stage (2). While each specimen point  $X_p, Y_p$  is being traveled to with the scanning stage (2) the relevant specimen height position  $Z_p$  is already being set, so that running errors of the scanning stage (2) are compensated for and image acquisi-

tions or measurements are possible immediately upon reaching the specimen point  $X_p, Y_p$ .